DEVICE OI INACTIVE FOR NEW	REVISIONS				
DESIGN AS OF 22 SEPTEMBER 1978. USE M38510/30906B	LTR	DESCRIPTION ***	DATE	APPROVED	
	С	Add logic diagram. Revise to military format. Delete vendors CAGE 34335, 07263, and 27014. Change $I_{\rm CC1}$, $I_{\rm CC2}$, and $t_{\rm PLH2}$. Add footnote $\underline{3}/.$ Allow $C_{\rm L}$ = 45 pF testing. Editorial changes throughout.	31 DEC 1987	MAGE	

CURRENT CAGE CODE 67268 REV PAGE REV **REV STATUS OF PAGES PAGES** 10 **Defense Electronics Supply Center** This drawing is available for use by all Departments and Agencies of the Dayton, Ohio Department of Defense TITLE: MICROCIRCUITS, DIGITAL, BIPOLAR, LOW POWER SCHOTTKY TTL, MULTIPLEXER, MONOLITHIC SILICON Original date of drawing: CODE IDENT. NO. 24 November 1976 SIZE DWG 76037 14933 Α REV AMSC N/A PAGE С 11

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SCOPE 1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices". 1.2 Part number. The complete part number shall be as shown in the following example: 76037 Case outline Lead finish per Drawing number Device type MIL-M-38510 (1.2.1)(1.2.2)1.2.1 Device type. The device type shall identify the circuit function as follows: Device type Generic number Circuit function 01 54LS257 Quad two-input data selector/multiplexer, three-state outputs, with enable 1.2.2 <u>Case outlines</u>. The case outlines shall be as designated in MIL-M-38510, appendix C and as follows: Outline letter Case outline D-2 (16-lead, 1/4" x 7/8"), dual-in-line-package F-5 (16-lead, 1/4" x 3/8"), flat package F 1.3 Absolute maximum ratings. -0.5 V dc to +7.0 V dc -1.5 V dc at -18 mA to +7.0 V dc -65°C to +150°C Storage temperature - - - - - - - - - - - - - - - - - - Maximum power dissipation (P_D) 1/ - - - - - - - Lead temperature (soldering, 10 $\overline{\text{seconds}}$) - - - - - -93.5 mW +300 °C Thermal resistance, junction-to-case (θ_{JC}): See MIL-M-38510, appendix C +175°C 1.4 Recommended operating conditions. 4.5 V dc minimum to 5.5 V dc maximum 2.0 V dc $\,$ 0.7 V dc -55°C to +125°C 1/ Must withstand the added P_D due to short circuit test (e.g. I_{OS}). **STANDARDIZED** SIZE

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2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
 - 3. REQUIREMENTS
- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.
 - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
 - 3.2.3 Logic diagram. The logic diagram shall be as specified on figure 3.
 - 3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full recommended case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

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	TABLE	I. Electr	ical perf	ormanc	e chara	cterist	ics.			
Test	 Symbol	Conditions -55°C < T _C < +125°C unless otherwTse specified			 Group subgro		Limi Min	ts Max	 Unit 	
High level output voltage	I V _{OH}		5 V; I _{OH} =	-1.0	mA	1, 2,	3	2.4		i v
Low level output voltage	V _{OL}	V _{CC} = 4.9	5 V; I _{OL} =	12 mA 0.7 V		1, 2,	3		0.4	V
Input clamp voltage	Y _{IC}	V _{CC} = 4.5	C:	-18 n	ıA	1			-1.5	V
Low level input current at A, B, or output control	I _{IL1}	V _{CC} = 5.	5 V, V _{IL} =	0.4 V	· · · · · · · · · · · · · · · · · · ·	1, 2,	3		-0.4	l mA l
Low level input current at select	II _{IL2}	V _{CC} = 5.	5 V, V _{IL} =	0.4 \		1, 2,	3		-0.8	i mA
current at A, B, or	I _{IH1}	V _{CC} = 5.	5 V, V _{IH} =	2.7 V		1, 2,	3		20	l μA
output control	 I _{I H2} 	V _{CC} = 5.	5 V, V _{IH} =	7.0 V		1, 2,	3		100	 μ Α
High level input current at select	I IH3	V _{CC} = 5.	5 V, V _{IH} =	2.7 V		1, 2,	3		40	! μ A
	 I _{I H} 4 	V _{CC} = 5.	5 V, V _{IH} =	7.0 V	1	 1, 2, 	3		 200 	l μ Α
Off state output IOZL VC		V _{CC} = 5.	5 V, V ₀ =	0.4 V	·	1, 2,	3		-20	 μ Α
	I Iozh I	V _{CC} = 5.	5 V, V ₀ =	2.7 V		1, 2,	3		20 	 μ Α
Short circuit output current	Ios	V _{CC} = 5.	5 V, V _{OUT}	= 0.0	V <u>1</u> /	1, 2,	3	-15	-130	i mA
Current supply	I _{CC1}	V _{CC} = 5.5 = 5.5 V, = 0.0 V	V, V _{IN} (V _{IN} (data) ut con	trol)	1, 2,	3		12	mA
	I _{CC2}	 V _{CC} = 5.! = 0.0 V, = 0.0 V	5 V, V _{IN} (V _{IN} (outp	data) ut con	itrol)	1, 2,	3		18 18	l mA l mA
	I _{CC3}	 Y _{CC} = 5.5 V _{IN} (outp	5 V out contro	1) = 5	.5 V	1, 2,	3		19	mA
See footnotes at end of	table.				· · · · · · ·					
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TABLE I. Electrical performance characteristics - Continued. Test Symbol Conditions Group A Unit Limits -55°C < T_C < +125°C unless otherwise specified subgroups Min Max 7 Functional tests See 4.3.1c $V_{CC} = 5.0 \text{ V}$ $R_L = 2 \text{ k} \Omega \pm 5\%$ $\frac{2}{3}$ $|C_L| = 5 pF \pm 10\%$ Propagation delay t_{PHL1} 9 18 ns time, from data to Y 25 10, 11 ns C_L = 50 pF ±10% 9 23 ns 10, 11 35 ns 9 18 |C_L = 5 pF ±10% tPLH1 ns 10, 11 25 ns |C_L = 50 pF ±10% 9 23 ns 10, 11 35 ns $|C_L = 5 pF \pm 10\%$ Propagation delay tpHL2 9 21 ns time, from select to Y 10, 11 29 ns ICL = 50 pF +10% 9 26 ns 10, 11 39 ns CL = 5 pF ±10% 9 21 ns tPLH2 29 10, 11 ns 9 $|C_1| = 45 \text{ pF} \pm 10\%$ 24 ns 10, 11 34 ns |C_L = 50 pF ±10% 9 26 ns 10, 11 39 ns See footnotes at end of table. **STANDARDIZED** SIZE

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TABLE I. Electrical performance characteristics - Continued.										
Test	 Symbol 	Conditions -55°C ≤ T _C ≤ +125°C		Group A Subgroups	Limits		 Unit 			
	<u> </u>	unless otherw		Min	Max					
Enable time, from output control to Y	t _{PZL1}		 C _L = 5 pF ±10%	9		30	ns			
output control to 1	ļ	$\begin{bmatrix} 2/3/3 \end{bmatrix}$		10, 11		42	l ns			
		! [CL = 50 pF ±10%	9		35	ns			
	<u> </u>	11	11	10, 11		53	ns			
	t _{PZH1}		1	CL =	! C _L = 5 pF ±10%	9		30	ns	
		1	1	10,11	!	42	ns			
	!	!	j	CL	C _L = 50 pF ±10	 C _L = 50 pF ±10%	9		35	ns
		ļ	[10, 11		53	ns			
Disable time from tpLZ1	1	C _L = 5 pF ±10%	9	, <u></u>	25	ns_				
output control to Y			10, 11		35	ns				
	!	<u> </u>	CL = 50 pF ±10%	9		30	ns			
	 -		10, 11		45	ns				
	t _{PHZ1}	1	C _L = 5 pF ±10%	9		30	ns			
	!		!	10, 11		42	ns			
	!	! !	 C _L = 50 pF ±10%	9		46	l ns			
		!		10, 11		60	ns			

Not more than one output should be shorted at a time, and the duration of the short circuit

 $3/R_{L}$ can be tested using $R_{L}=2~k\Omega$ or $R_{L}=667\Omega$.

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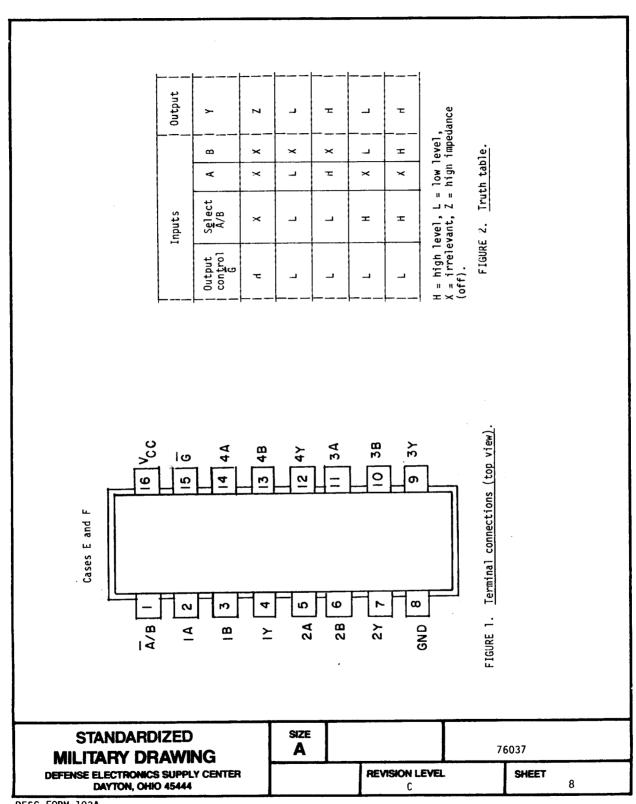
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rondition should not exceed one second.

Propagation delay time, enable time, and disable time testing may be performed using either $C_L = 5$ pF, $C_L = 45$ pF, or $C_L = 50$ pF. However, the manufacturer must certify and guarantee that the microcircuits meet the switching test limits specified for a 50 pF load.

- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
 - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test (method 1015 of MIL-STD-883).
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 4, 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - c. Subgroup 7 tests shall verify the truth table specified on figure 2 herein.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
 - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
 - (2) $T_A = +125^{\circ}C$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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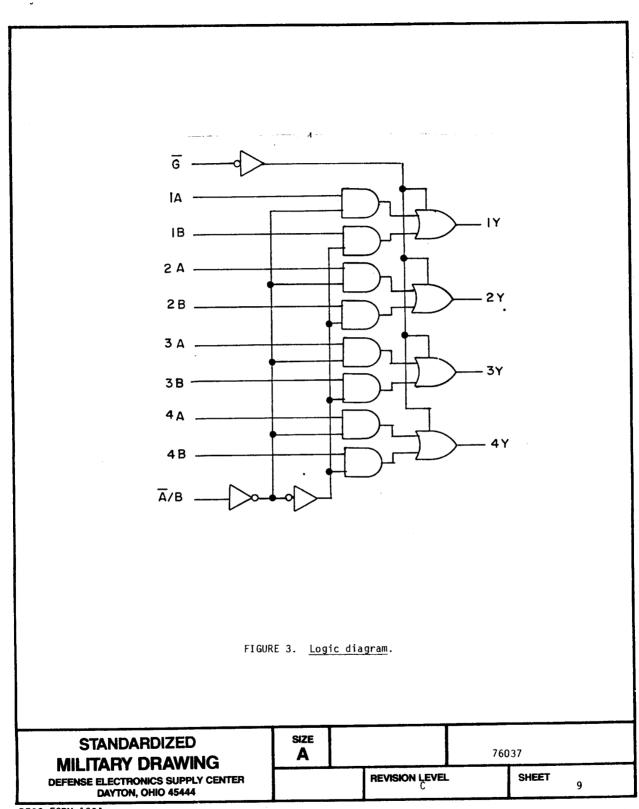


TABLE	II.	Electrical	test	requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 7, 9 10, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

PDA applies to subgroup 1 (see 4.2c).
 Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
 - 6.2 Replaceability. Replaceability is determined as follows:
 - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
 - b. When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/30906B--.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/	Replacement military specification part number
7603701EX <u>2</u> /	01295 04713 18324	SNJ54LS257BJ 54LS257/BEAJC 54LS257A/BEA	M38510/30906BEX
7603701FX <u>2</u> /	01295 04713 18324	SNJ54LS257BW 54LS257/BFAJC 54LS257A/BFA	M38510/30906BFX

^{1/} Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

2/ Inactive for new design. Use QPL device.

Vendor CAGE number	Vendor name and address
01295	Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701
04713	Motorola, Incorporated 7402 South Price Road Tempe, AZ 85283
18324	Signetics Corporation 4130 South Market Court Sacramento, CA 95834

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